SRS 2003 Seminar

Learn new professional skills you need in a rewarding and
easily absorbed class on SRS Analysis.
- presented without unneeded equations and focused on applications -
by a pioneer of SRS for shock and package testing.

Class Syllabus - 41 Topics

Introduction & history	SRS of sine excitation
What is SRS?	The classic SRS responses
Time or frequency domain?	The true half sine SRS
Reasons to use SRS	The true trapezoid SRS
Major applications of SRS	SRS rules
Basic SRS theory	Effects of residual spectrum
What is an SDOF?	Residual spectrum errors
How do SDOFs respond?	Example of typical SRS applications
Damping controls response	The BellCor seismic SRS using "zones"
Initial and residual response	Fragility SRS using DB Template
Response of SDOFs to excitation	Develope a DB template using SRS
The resulting spectral envelope	Drop test with fragility template
How are SRS's produced?	Determine actual drop height using SRS
Reading the SRS	Validating a shock
The Maximax plot	Procurement Spectification Test
Damping and its effects	SRS vs FFT for envelope detection
Amplification of SDOF	Standarization of shock machines
Linear f plot and SDOF overlaps	PyroShock analysis using SRS
Log f plot and normal filter spacing	Replication of field events using SRS
Typical SDOF gain cases	SRS model requirements

Added bonus: Inappropriate SRS Spectification used by PC Manufacturer

Attendees will receive a CDROM with presentation slides, reference material, and a data acquisition simulator with full SRS analyzer and digitized shock files. The simulator can recall shocks and process SRSs in various modes to illustrate the seminar material.

One half day Seminar. Additional time for lab demonstrations may be arranged Contact sponsor for schedule and registration cost. Or call
800-444-7978
Sponsor reserves the right to cancel this program at any time prior to seven days before Seminar. Registration will be refunded.

GHI SYSTEMS

The Seminar Instructor is George Henderson well know authority in SRS applications. Mr. Henderson has been active in package and shock test fields for over 30 years. He has published numerous papers and conducts seminars on SRS and spectrum analysis, including an invited paper describing SRS at the JIS in Tokyo, when Japan adopted SRS. Mr. Henderson has consulted for IBM, Boeing, Ford Motors, Dell Computers, Maxtor Corporation, University of Maryland CALCE and many. In the late 1970's he pioneered the field of PC based computer aided testing (CAT) systems, and developed the first PC based SRS software product in conjunction with Sandia Corporation. He is a member of several professional associations including ASTM, IOPP, IEST, ISA and SAE.

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